

# STY30NK90Z

## N-channel 900V - 0.21Ω - 26A - Max247 Zener-protected SuperMESH™ Power MOSFET

## **General features**

Туре	V <sub>DSS</sub>	R <sub>DS(on)</sub>	۱ <sub>D</sub>	р <sub>W</sub>
STY30NK90Z	900V	<0.26Ω	28A	500W

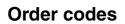
- Extremely high dv/dt capability
- 100% avalanche tested
- Gate charge minimized
- Very low intrinsic capacitances
- Very good manufacturing repeatibility

## Description

The SuperMESH<sup>™</sup> series is obtained through an extreme optimization of ST's well established strip-based PowerMESH<sup>™</sup> layout. In addition to pushing on-resistance significantly down, special care is taken to ensure a very good dv/d capability for the most demanding applications. Such series complements ST full range of high voltage MOSFETs including reirclutionary MDmesh<sup>™</sup> products.

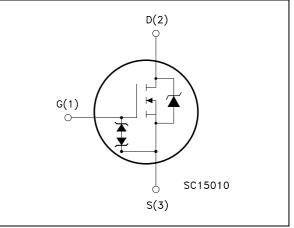
## Applications

Switching application



Max247	

## Internal schematic diagram



Part number	Marking	Package	Packaging
STY30NK90Z	Y30NK90Z	Max247	Tube

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### 1

# **Electrical ratings**

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source voltage ( $V_{GS} = 0$ )	900	V
V <sub>GS</sub>	Gate- source voltage	± 30	V
۱ <sub>D</sub>	Drain current (continuous) at $T_C = 25^{\circ}C$	26	А
۱ <sub>D</sub>	Drain current (continuous) at T <sub>C</sub> = 100°C	16	А
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	104	A
P <sub>tot</sub>	Total dissipation at $T_{C} = 25^{\circ}C$	450	Ŵ
	Derating Factor	3.57	W/°C
V <sub>ESD(G-S)</sub>	Gate source ESD(HBM-C=100pF, R=1.5KΩ)	50.78	V
dv/dt (2)	Peak diode recovery voltage slope	1.5	V/ns
T <sub>stg</sub>	Storage temperature	CE 45 150	ŝ
Тj	Max. operating junction temperature	-65 to 150	°C

1. Pulse width limited by safe operating area.

2.  $I_{SD} \leq 6A$ , di/dt  $\leq 400A/\mu s$ ,  $V_{DD} \leq V_{(BR)DSS}$ ,  $T_{J} \leq T_{I_{h}, AX}$ 

#### Table 2. Thermal data

Rthj-case	Thermal resistance junction-case max	0.277	°C/W
Rthj-amb	Thermal resistance junction-ambient max	30	°C/W
TJ	Maximum lead temperature for soldering purpose	300	°C

#### Table 3. Avalanche characteristics

	Table 3.	Avalanche characteristics		
10	Symbol	Parameter	Max value	Unit
00501	I <sub>AR</sub>	Avalanche current, repetitive or not-repetitive (pulse width limited by $T_j$ max)	26	А
05	E <sub>AS</sub>	Single pulse avalanche energy (starting $T_j = 25 \text{ °C}$ , $I_D = I_{AR}$ , $V_{DD} = 35 \text{ V}$ )	500	mJ

#### Table 4. Gate-source zener diode

ĺ	Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
	BV <sub>GSO</sub>	Gate-source breakdown voltage	Igs=± 1mA (open drain)	30			V



### **1.1** Protection features of gate-to-source zener diodes

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The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.



#### 2 **Electrical characteristics**

(T<sub>CASE</sub>=25°C unless otherwise specified)

	on/on states					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	I <sub>D</sub> = 1mA, V <sub>GS</sub> =0	900			v
I <sub>DSS</sub>	Zero gate voltage drain current (V <sub>GS</sub> = 0)	$V_{DS}$ = max rating $V_{DS}$ = max rating, $T_{C}$ = 125°C			10 100	μΑ Αυ
I <sub>GSS</sub>	Gate-body leakage current (V <sub>DS</sub> = 0)	$V_{GS} = \pm 20V$		22	±100	μA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 150 \mu A$	3	3.7 <i>5</i>	4.5	V
R <sub>DS(on)</sub>	Static drain-source on resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 14A	R	0.21	0.26	Ω
Table 6.	Dynamic	olere				
		5		-		1114

#### Table 5. **On/off states**

#### Table 6. Dynamic

	Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
	9 <sub>fs</sub> <sup>(1)</sup>	Forward transconductance	V <sub>DS</sub> = 15V <sub>,</sub> I <sub>D</sub> = 14A		26		S
	C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input capacitonite Output capacitance Revense transfer capacitance	V <sub>DS</sub> = 25V, f = 1MHz, V <sub>GS</sub> = 0		12000 852 166		pF pF pF
	C <sub>oss eq</sub>	Equivalent output capacitance	$V_{GS} = 0V, V_{DS} = 0V$ to 720V		377		pF
opsole	<sup>t</sup> d(on) t <sub>r</sub> <sup>t</sup> d(off) t <sub>f</sub>	Turn-on delay time Rise time Turn-off delay time Fall time	$V_{DD} = 450V, I_D = 13A$ $R_G = 4.7\Omega V_{GS} = 10V$ (see <i>Figure 13</i> )		67 59 250 72		ns ns ns ns
	Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total gate charge Gate-source charge Gate-drain charge	$\begin{split} V_{DD} &= 720 \text{V}, \text{I}_{D} = 26 \text{A}, \\ V_{GS} &= 10 \text{V}, \text{R}_{G} = 4.7 \Omega \\ (\text{see Figure 14}) \end{split}$		350 51 190	490	nC nC nC

1. Pulsed: Pulse duration = 300  $\mu$ s, duty cycle 1.5 %.

2. Coss eq. is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}.$ 



1	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub> I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current Source-drain current (pulsed)				28 112	A A
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	I <sub>SD</sub> = 28A, V <sub>GS</sub> = 0			2	V
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 26A, di/dt = 100A/\mu s,$ $V_{DD} = 100V, T_j = 25^{\circ}C$ (see <i>Figure 15</i> )		1 18.9 36.6		μs μC A
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 26A, di/dt = 100A/\mu s,$ $V_{DD} = 100V, T_j = 150^{\circ}C$ (see <i>Figure 15</i> )		1.33 25.2 37.8		μs ,ιC A
	th limited by safe operating are	a		<u> </u>		
		5010				
	Juct(S)	V <sub>DD</sub> = 100V, 1 <sub>j</sub> = 150°C (see <i>Figure 15</i> ) a. cle 1.5 %				

Table 7. Source drain diode

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GC7562

 $Z_{th} = KR_{thJ-c}$ 

 $10^{0} t_{p}(s)$ 

 $\delta = t_p / \tau$ 

10-1

10-2

**Thermal impedance** 

 $\delta = 0.05$ 

 $\delta = 0.01$ 

10<sup>-4</sup>

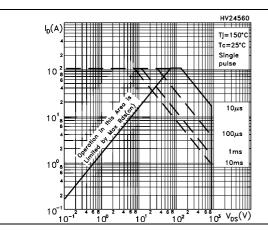
=0.02

10<sup>-3</sup>

Transfercheracteristics

## 2.1 Electrical characteristics (curves)

### Figure 1. Safe operating area





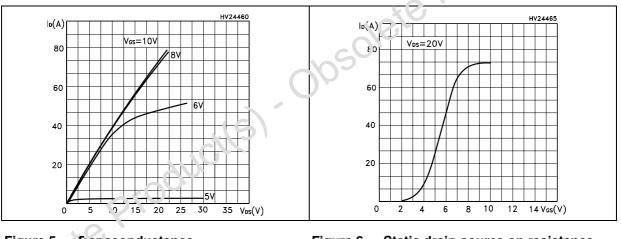


Figure 2.

Κ

10<sup>0</sup>

10

 $10^{-3}$ 

Figure 4.

10<sup>-5</sup>



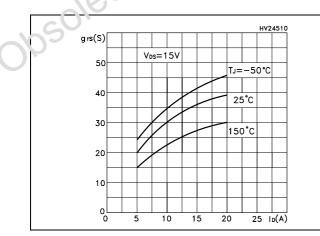
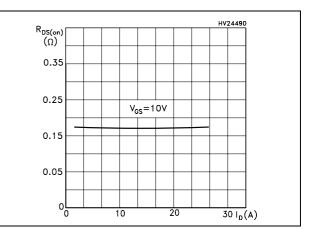


Figure 6. Static drain-source on resistance



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### Figure 7. Gate charge vs gate-source voltage Figure 8. Capacitance variations

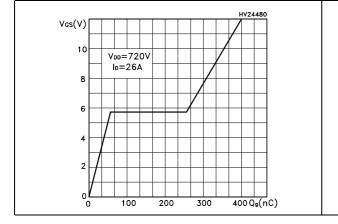


Figure 9. Normalized gate threshold voltage vs temperature

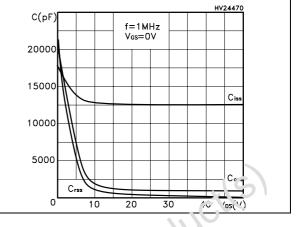


Figure 10. Normalized on resistance vs temperature

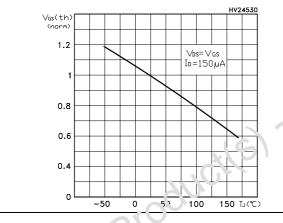


Figure 11. Source arain diode forward characteristics

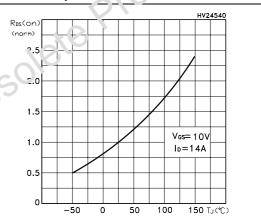
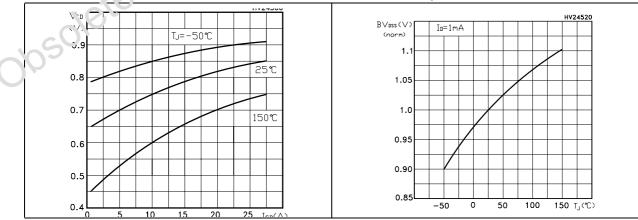
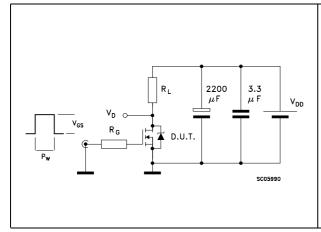


Figure 12. Normalized breakdown voltage vs temperature



## 3 Test circuit

Figure 13. Switching times test circuit for resistive load



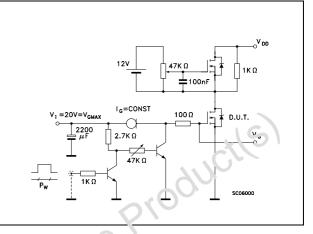
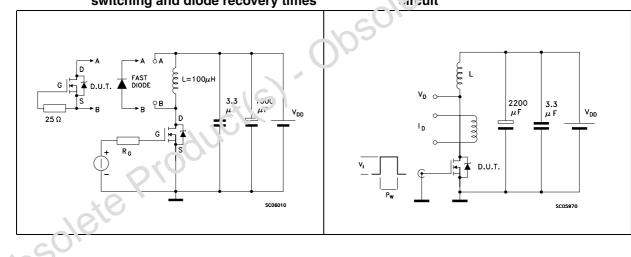


Figure 14. Gate charge test circuit

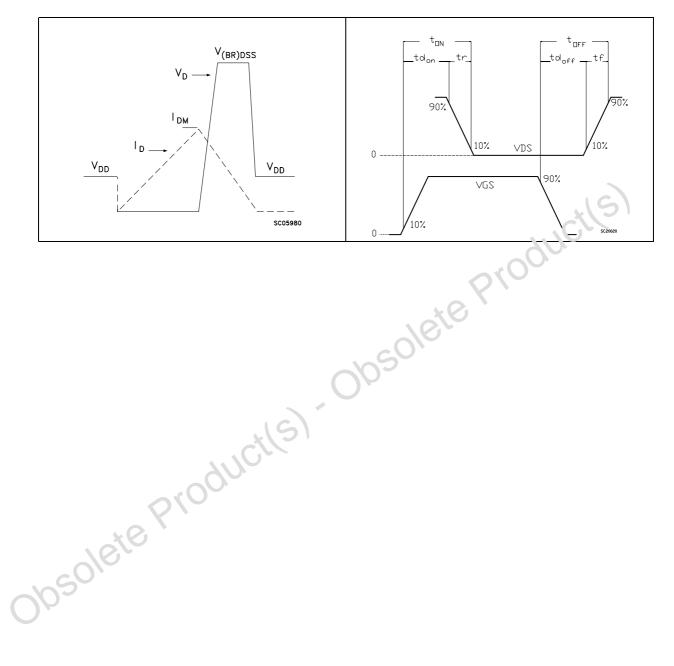
Figure 15. Test circuit for inductive load switching and diode recovery times

Figure 16. Unclumped Inductive load test



### Figure 17. Unclamped inductive waveform

### Figure 18. Switching time waveform



## 4 Package mechanical data

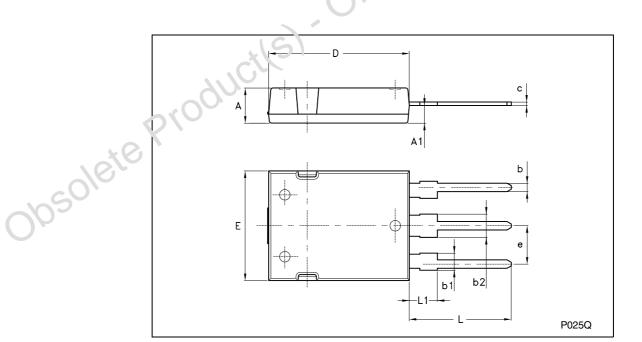
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DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	4.70		5.30			
A1	2.20		2.60			
b	1.00		1.40			
b1	2.00		2.40			
b2	3.00		3.40		11	
с	0.40		0.80			
D	19.70		20.30		10	
е	5.35		5.55			
E	15.30		15.90	× 0,		
L	14.20		15.20	0		
L1	3.70		4.30			

### Max247 MECHANICAL DATA





## 5 Revision history

### Table 8. Revision history

	Date	Revision	Changes
	16-Jul-2004	1	First release
	23-Mar-2004	2	New ECOPACK label inserted
	21-Jan-2005	3	Complete document with curves
	16-Oct-2006	4	New template, no content change
obsole	teprod	Jucils	New template, no content change



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